

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L28	0	(integrated circuit AND circuit under test AND DUT AND scan chain AND compressor AND decompressor AND phase shifter AND compressed test pattern AND decompressed test pattern AND LFSM AND linear finite state machine AND circuit logic).clm.	US-PGPUB; USPAT; USOCR	ADJ	ON	2008/09/24 18:36

9/ 24/ 08 6:36:38 PM

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